

Designation: D7127 - 05 D7127 - 13

Standard Test Method for **Measurement of Surface Roughness of Abrasive Blast** Cleaned Metal Surfaces Using a Portable Stylus Instrument¹

This standard is issued under the fixed designation D7127; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ε) indicates an editorial change since the last revision or reapproval.

1. Scope

- 1.1 This test method describes a shop or field procedure for determination of four-roughness characteristics of surfaces prepared for painting by abrasive blasting. The procedure uses a portable skidded or non-skidded stylus profile tracing instrument. The three measured characteristics are: Rt and Rpc. Additional measures of profile height (Rmax and/or Rz) may also be obtained as agreed upon by purchaser and seller. (The digitally-determined profile parameters Rt,Rmax,Ry and Pe.Rzlmax are extremely similar in definition.)
 - 1.2 The values stated in SI units are to be regarded as the standard. The values given in parentheses are for information only.
- 1.3 In general, this method should be limited to the measurement of surface roughness where *RmaxRt* is in the range 10 to 150 μm (0.4 to 6 mil) and where the Peak Count, *Pc*,*Rpc* is less than 180 peaks/cm (450 peaks/in.).
- 1.4 This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.

2. Referenced Documents

2.1 ASTM Standards:²

D4417 Test Methods for Field Measurement of Surface Profile of Blast Cleaned Steel

E177 Practice for Use of the Terms Precision and Bias in ASTM Test Methods

E691 Practice for Conducting an Interlaboratory Study to Determine the Precision of a Test Method

2.2 ASME Standard:

ASME B46.1-2002 Surface Texture, Surface Roughness Waviness and Lay³

ISO 4287: 1997 Geometrical Product Specifications (GPS)—Surface Texture: Profile Method—Terms, Definitions, and Surface Parameters⁴

3. Terminology

- 3.1 Definitions—The following definitions are provided as an aid to users of this document. Formal definitions of the surface roughness and instrument parameters below are contained in the referenced standards (Fig. 1).
- 3.1.1 deadband, n—that distance above and below the mean line that a continuous trace line must cross in both directions (up and down) to count as a single peak.

3.1.1.1 Discussion—

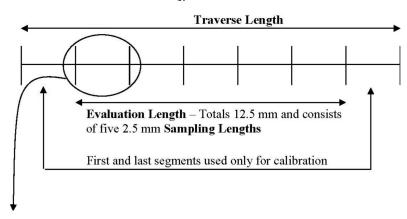
¹ This test method is under the jurisdiction of ASTM Committee D01 on Paint and Related Coatings, Materials, and Applications and is the direct responsibility of Subcommittee D01.46 on Industrial Protective Coatings.

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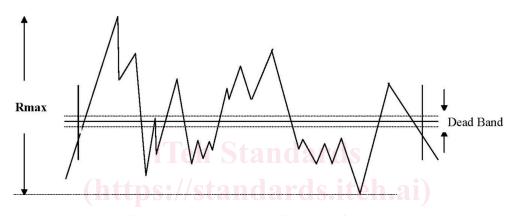
² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For Annual Book of ASTM Standards volume information, refer to the standard's Document Summary page on the ASTM website.

³ Available from American Society of Mechanical Engineers (ASME), ASME International Headquarters, Three Park Ave., New York, NY 10016-5990.10016-5990, http://www.asme.org.

Available from International Organization for Standardization (ISO), 1-rue de Varembé, Case postale 56, CH-1211, Geneva 20, Switzerland. 1, ch. de la Voie-Creuse, CP 56, CH-1211 Geneva 20, Switzerland, http://www.iso.org.



Below: Expanded view of a single Sampling Length



Top — Illustration of stylus device terminology: sampling length, evaluation length, traverse length.

Bottom — Expanded view of a single sampling length to illustrate surface structure terminology:

Rt: difference between highest peak and lowest valley over the evaluation length.

Rmax: difference between highest peak and lowest valley over the sampling. length

Pc: number of peak/valley pairs, per unit length extending outside a deadband centered on the mean line.

FIG. 1 Illustration of Terminology

Use of a deadband diminishes the effect of small, spurious peaks due to noise.

- 3.1.2 evaluation length, n—a sequence of five consecutive sampling lengths.
- 3.1.3 Pc, Rpc, n—the number of peak/valley pairs, per unit of length, extending outside a "deadband" centered on the mean line.
- 3.1.4 Rt, n—the vertical distance between the highest peak and lowest valley within any given evaluation length.
- 3.1.5 Rmax, n—the largest peak to valley measurement is determined from greatest vertical distance between highest peak and lowest valley for any of the five sampling lengths, and the largest of these five values is lengths that comprise an evaluation length.Rmax.
- 3.1.6 *Rt*; *Rz*, *n*—the <u>vertical</u> distance between the highest peak and the <u>lowest valley within any given lowest valley in a sampling</u> length averaged over the five sampling lengths comprising the evaluation length.
- 3.1.7 *sampling length*, *n*—the nominal interval distance parallel to the surface being assessed within which a single value of a surface parameter is determined.
- 3.1.8 *surface preparation*, *n*—the cleaning and profiling of a metallic surface using an abrasive blast media or mechanical means to prepare that surface for coating.
- 3.1.9 *surface profile, n—for purposes of the standard*, the positive and negative vertical deviations (peaks and valleys) are measured from a mean line approximately the center of the profile being evaluated.



- 3.1.10 *surface roughness*, *n*—the combined characteristics of surface profile (height) and peak count (linear density) for a surface.
- 3.1.11 traversing length, n—seven sampling lengths comprising the evaluation length and the pre-travel and post-travel segments.

4. Summary of Test Method

- 4.1 This test method describes the proper use of a portable stylus surface roughness measuring device to evaluate specific surface parameters and evaluate their suitability for the application of the selected coating to the surface being prepared by abrasive blasting, or other mechanical means, prior to application.
- 4.2 The method describes considerations relevant to setup of stylus instruments for acquisition of required surface roughness parameters.

5. Significance and Use

- 5.1 This method may be useful in assuring conformance of a prepared surface to profile requirements specified by the manufacturer of a protective coating.
- 5.2 This method includes determination of the peak density (number of profile peaks in a specified distance). Some workers in the field believe that optimizing peak height and peak density can improve coating adhesion.
- 5.3 This method allows specifiers to objectively define surface texture after abrasive blast cleaning rather than using subjective terms such as "angular pattern" or "dense and uniform pattern."
- 5.4 Because implicit and explicit definitions of "roughness" may differ substantially, numerical characterizations of profile cannot be compared directly across different methods.

6. Apparatus

- 6.1 The apparatus consists of a portable skidded or non-skidded electronic surface roughness measurement instrument ("tester") capable of measuring *Rt*; *Rt*Rmax in compliance with ISO 4287 and *PeRpc* in compliance with ASME B46.1. The apparatus should have a vertical range of at least 300 µm (12 mil) and permit a sampling length of 2.5 mm (0.1 in.) and an evaluation length of 12.5 mm (0.5 in.). (Laboratory experience suggests this vertical range is a practical requirement to meet the provisions of 6.2.) In 20042009 there are believed to be at least five manufacturers three manufactures of such devices.⁵
- 6.2 The apparatus should include a stylus with a tip radius of 5 μ m (0.2 mil), and permit recording of Rt and Rmax in the range 10 to 150 μ mmm (0.4 to 6 mil) and Rmax up to 180/cm (450/in.).
- 6.3 Surface deviations are sensed by the stylus and converted to electrical signals within the device. Internal processing converts these signals into standard surface characterization parameters, which are then displayed or printed.

7. Preparation of Apparatus

- 7.1 Set the apparatus to display, and, if so equipped, record the chosen parameters in accordance with the manufacturers' instructions.
- 7.2 The evaluation length should be set to 5 sampling lengths. The sampling length and evaluation length should be set to 2.5 μ mmm (0.1 in.) and 12.5 μ mmm (0.5 in.), respectively.
- 7.3 The traversing length of the apparatus should be set (or manufacturer preset) to include pre-travel and post-travel segments, usually equal to one sampling length at the beginning and one sampling length at the evaluation length. These portions of a traverse are, however, discarded by the instrument in its calculation of surface parameters.
- 7.4 The low frequency ("long wavelength" or "cutoff") filter should be set to "Gaussian" or "Gaussian 50 %." In general, the default setting will be compliant.
 - 7.5 If the apparatus has a high frequency ("short wavelength" or "Ls") filter should be set to "off."
- 7.6 The apparatus should be adjusted (if necessary) to a deadband width (C1 = -C2) in the range 1.00.5 to 1.252.0 µm $(40(20 \pm 0.5080)$ µin.). The choice of deadband for profiles as large as those discussed in this standard will have little effect on the measurements. In general, the default setting will be compliant.
- 7.7 The <u>accuracy of the apparatus</u> should be <u>ealibrated checked</u> regularly using a <u>standard</u> calibration block available from the equipment manufacturer using their written <u>ealibration setup</u> procedure (<u>and Fig. 1</u>).at their recommended interval.

8. Preparation of the Sample

8.1 Select a 15 by 15 cm (6 by 6 in.) an area of the surface to be tested that is visibly free from obvious defects such as scratches, deep marks, or other construction or corrosion defects.

⁵ Research Report to be developed with a listing of manufacturers.